

**Amendments to the Specification:**

Please replace the paragraph beginning at page 4, line 34, with the following replacement paragraph:

--The beam reflected at incidence point P, in the form of reflected beam 10, passes, in a receiving optical system, through a rotationally driven analyzer 5.4, a filter 5.5, and a converging lens 5.6, and is focused by the latter onto a photodetector 5.7. Photodetector 5.7 belongs to a photodetector device that detects on the one hand intensity fluctuations of reflected beam 10, and on the other hand the incidence location on photodetector 5.7. Photodetector 5.7 can be, for example, a position-sensitive detector (PSD) or a CCD camera. A position measuring instrument 7.1 for an X and/or Y position is provided in evaluation device 7. The distance from incidence point P is taken into account when the X and/or Y angle is calculated. Also provided is an intensity measuring instrument 7.2 that senses the intensity fluctuations of reflected beam 10 resulting from the rotation of analyzer 5.4 [[5.7]] and serves to calculate the ellipticity.--.